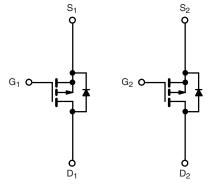


## SI6969BDQ-T1-GE3-VB Datasheet

### Dual P-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	<b>R<sub>DS(on)</sub> (</b> Ω <b>)</b>	I <sub>D</sub> (A) <sup>d</sup>	Q <sub>g</sub> (Typ.)	
	0.013 at V <sub>GS</sub> = - 4.5 V	-7.5		
- 20	0.018 at V <sub>GS</sub> = - 2.5 V	-6.5	20 nC	
	0.032 at V <sub>GS</sub> = - 1.8 V	-5.0		



P-Channel MOSFET P

P-Channel MOSFET

#### **FEATURES**

- Halogen-free According to IEC 61249-2-21
  Definition
- Trench Power MOSFET
- 100 % Rg Tested
- 100 % UIS Tested
- Compliant to RoHS Directive 2002/95/EC

#### **APPLICATIONS**

- Adaptor Switch
- High Current Load Switch
- Notebook





ABSOLUTE MAXIMUM RATINGS ( $T_A$	= 25 °C, unless oth	erwise noted	d)		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V <sub>DS</sub>	- 20	v	
Gate-Source Voltage		V <sub>GS</sub>	± 12	v	
	T <sub>C</sub> = 25 °C		- 7.5		
Continuous Drain Current (T. 150 °C)	T <sub>C</sub> = 70 °C		- 6.0		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	- 5.4 <sup>a, b</sup>		
	T <sub>A</sub> = 70 °C		- 4.5 <sup>a, b</sup>		
Pulsed Drain Current		I <sub>DM</sub>	- 30	A	
	T <sub>C</sub> = 25 °C		- 4.1		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	- 2.1 <sup>a, b</sup>		
Avalanche Current	1 0.1 mll	I <sub>AS</sub>	- 15		
Single-Pulse Avalanche Energy	ergy L = 0.1 mH		11.25	mJ	
	T <sub>C</sub> = 25 °C		5		
Maujanum Dauga Diasia atian	T <sub>C</sub> = 70 °C		3.2	w	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.5 <sup>a, b</sup>	vv	
	T <sub>A</sub> = 70 °C		1.6 <sup>a, b</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a, c</sup>	t ≤ 10 s	R <sub>thJA</sub>	38	50	°C/W	
Maximum Junction-to-Foot	Steady State	R <sub>thJF</sub>	20	25		

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. t = 10 s.

c. Maximum under steady state conditions is 85  $^{\circ}\text{C/W}.$ 

d. Based on T<sub>C</sub> = 25 °C.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				, ,,		I	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = - 250 μA	- 20			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			- 14.5		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	ΔV <sub>GS(th)</sub> /T <sub>J</sub>	I <sub>D</sub> = - 250 μA		2.8			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	- 0.4		- 1.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 8 V$			± 100	nA	
U U	I <sub>DSS</sub>	$V_{DS} = -20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1	1 uA	
Zero Gate Voltage Drain Current		$V_{DS} = -20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 70 \text{ °C}$			- 10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge -10 \text{ V}, \text{ V}_{GS} = -5 \text{ V}$	- 20			Α	
	B(01)	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 7 A		0.013			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = -2.5 \text{ V}, I_D = -6 \text{ A}$		0.018		Ω	
	20(01)	V <sub>GS</sub> = - 1.8 V, I <sub>D</sub> = - 3 A		0.032		1	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 10 V, I <sub>D</sub> = - 9 A		40		S	
Dynamic <sup>b</sup>	- 10			11			
Input Capacitance	C <sub>iss</sub>			2380		pF	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		340			
Reverse Transfer Capacitance	C <sub>rss</sub>			280			
•		V <sub>DS</sub> = - 10 V, V <sub>GS</sub> = - 8 V, I <sub>D</sub> = - 5 A		45	70	nC	
Total Gate Charge	Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>			20	35		
Gate-Source Charge		$V_{DS} = -10 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -5 \text{ A}$		3.1			
Gate-Drain Charge				8.4			
Gate Resistance	R <sub>q</sub>	f = 1 MHz	1.0	4.8	9.6	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			7	14	-	
Rise Time	t <sub>r</sub>	$V_{DD} = -10 V, R_1 = 2 \Omega$		9	18		
Turn-Off DelayTime		$I_D \cong -5 \text{ A}, \text{ V}_{\text{GEN}} = -8 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		108	200		
Fall Time	t <sub>f</sub>	, , , , , , , , , , , , , , , , , , ,		41	80	-	
Turn-On Delay Time	t <sub>d(on)</sub>			14	28	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = -10 V, R_1 = 2 \Omega$		16	32	-	
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong -5 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		101	200		
Fall Time	t <sub>f</sub>	Ŭ		40	80		
Drain-Source Body Diode Characteris				11			
Continous Source-Drain Diode Current	١ <sub>s</sub>	T <sub>C</sub> = 25 °C			- 4.1		
Pulse Diode Forward Current	I <sub>SM</sub>	Ŭ			- 40	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 3 A, V <sub>GS</sub> = 0 V		- 0.66	- 1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			81	150	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			150	300	nC	
Reverse Recovery Fall Time	ta	$I_F = -2.3 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^\circ\text{C}$		43		ns	
Reverse Recovery Rise Time	t <sub>b</sub>			38			

Notes:

a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

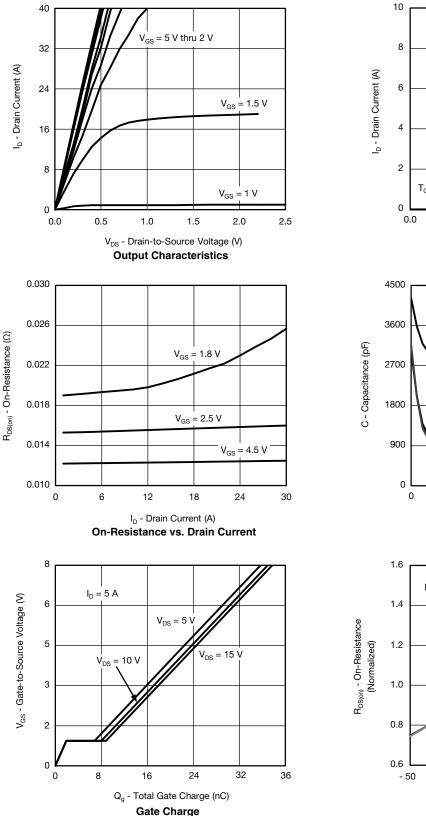
b. Guaranteed by design, not subject to production testing.

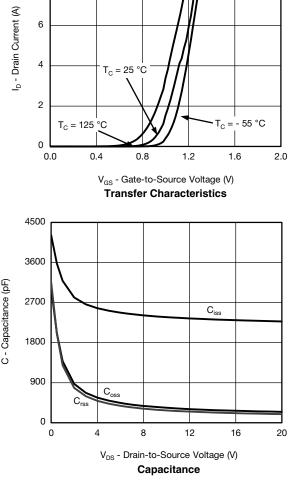
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

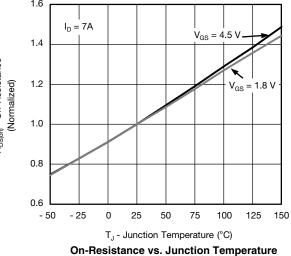
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#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

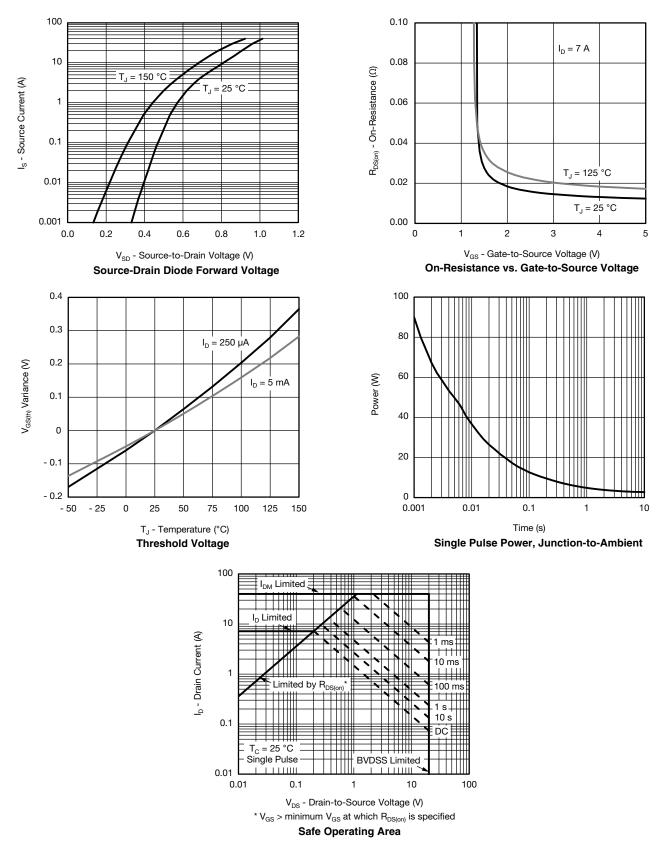






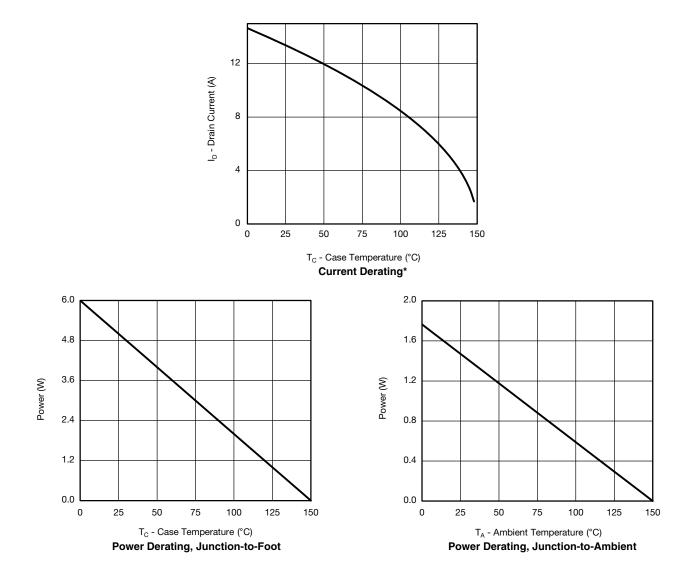








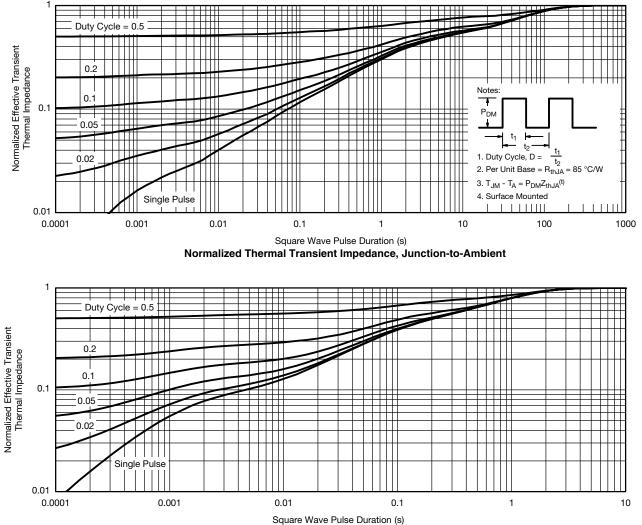
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



\* The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Foot



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